



PHYSICAL ELECTRONICS GMBH

der Bundeswehr
Universität München

New PHI XPS & Anasys Instruments SNOM + AFM-IR

Now, the Institute of Physics of the Universität der Bundeswehr München has an analysis and research laboratory that is unparalleled. With the two new acquisitions of the VersaProbe III with a UPS, the latest XPS system from Physical Electronics, the surface analysis laboratory has now been completed. In addition to the nanoTOF II, a TOF-SIMS also from Physical Electronics, the VersaProbe III will soon provide unique results in the development of novel components with low-dimensional materials.

Prof. Georg S. Düsberg has held the Chair of Sensor Technologies at the Institute of Physics of the Universität der Bundeswehr in Munich since 1 January 2017. In addition to the XPS, he also procured the nanoIR2-s from Anasys Instruments. The nanoIR2-s is an IR scattering SNOM, which means 3 technologies in one. The combination AFM-IR plus scattering SNOM. This technique provides information about the complex optical properties of the nano-scale region of the sample under a metallized tip. Prof. Düsberg's research covers carbon nanotubes, graphene and other 2D films. We can be curious.

PHI VersaProbe III



XPS the surface sensitive technique can generally obtain information on elements within a few nms of the sample surface.

nanoIR2-s



nanoIR2-s united two complementary nanoscale IR techniques, s-SNOM and AFM-IR. This combination creates remarkable new data and eliminates the need for complex optical alignments..

